

International Organization of Legal Metrology



OIML Seminar

What Will Legal Metrology Be In The Year 2020

- Complete Set of Presentations -

**Thursday 26 – Friday 27
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***Espace Olano
Saint-Jean-de-Luz, France***



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Introduction

Today's legal metrology is quite different from what it was some twenty years ago, both at national and at international levels. However, this evolution is accelerating and has to be anticipated both by legal metrology authorities as well as by manufacturers of measuring instruments, and of course by the OIML.

Legal metrology is, in fact, facing multiple developments:

- ❑ Globalization of economies and international trade,
- ❑ Free circulation of products,
- ❑ Geopolitical changes,
- ❑ The emergence of regional structures and simultaneously the fragmentation of countries or decentralization,
- ❑ Liberalization,
- ❑ Privatization and redefinition of the role of the State,
- ❑ Citizens' demand for better health and environmental protection,
- ❑ The possibility of measuring increasingly numerous aspects of everyday life,
- ❑ The considerable technological progress of measuring instruments, rapid development in information technologies and in the issues concerning security of information systems,
- ❑ And many more.

A number of countries are revising their law on metrology, reorganizing their legal metrology structures, reconsidering the scope of legal metrological control, and studying technical regulations adapted to new technologies. Such projects will determine the orientation of legal metrology for the coming decades and must be based on a long term perspective.

The OIML has developed a "Long Term Action Plan" with the objective of monitoring its activities for the next five years. A five-year term is indeed within the reach of most of those in charge of legal metrology services, but does not provide enough perspectives for the fundamental evolutions of legal metrology.

This Seminar was the opportunity for those in charge of legal metrology and industry to meet, step back from the "day to day" issues of legal metrology, and focus on the real long term views, 2020 being far enough away for participants to "disconnect" from today's

constraints, but close enough to have a realistic view of the future.

The event was held in conjunction with the 37th CIML Meeting and was open to all interested specialists from legal metrology services and industry.



Saint-Jean-de-Luz: Coast path



Saint-Jean: Louis IX Square



Ciboure: View from the Fort

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Note from the Editor concerning this transcript

The BIML contracted a local company to record the Seminar proceedings on audio cassette, including the question and answer sessions.

Unfortunately, the company concerned did not accomplish this task in a professional manner and as a result, parts of certain presentations and discussions were not recorded and can therefore not be transcribed in this report.

The BIML apologizes for this incident, which as readers will appreciate, was out of our control and the problem was only discovered after the event was over.

... and a Personal Note from the Editor

The Editor would like to express his most sincere thanks to Mr. Bernard Athané for his work in transcribing certain of these presentations from the audio cassettes and for ensuring that all the remaining texts were submitted on time by the Authors. His commitment and assistance are very much appreciated.

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Opening

The Seminar was organized and chaired by Mr. Bernard Athané, former BIML Director, who welcomed participants and then briefly explained the aims of the event and the way in which he intended to chair it. He then gave the floor to Mr. Gerard Faber, CIML President, for a more detailed introduction.